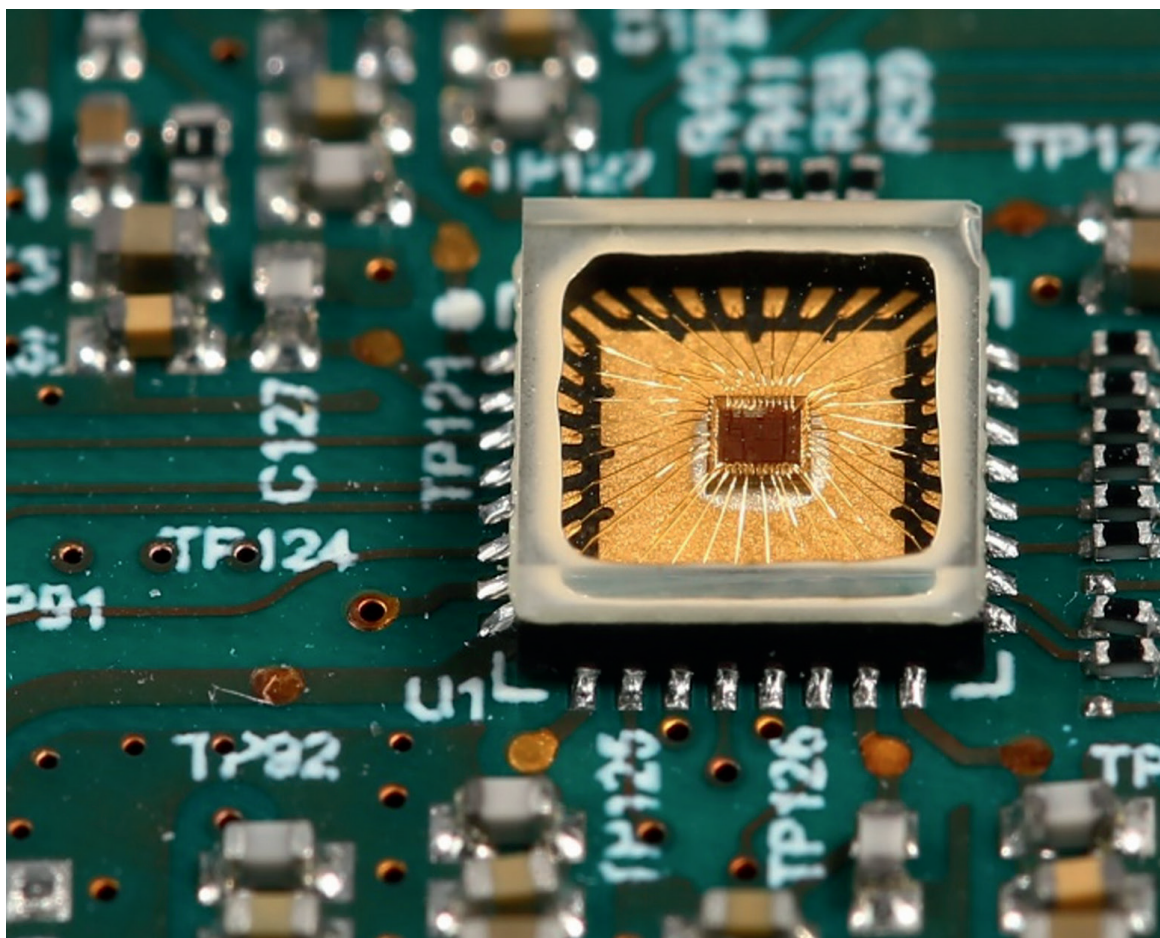




Software-Configurable Analog-To-Digital Converters for Configurable Pulse Detection

Lukas Krystofiak

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Contents

Acknowledgement	i
List of Figures	xi
List of Tables	xv
Acronyms	xvii
1 Introduction	1
1.1 Motivation	1
1.2 Outline of the Thesis	2
2 Fundamentals of the Analog-To-Digital Converter	5
2.1 Principle Theory of Operation	5
2.2 Fundamental Limits	6
2.2.1 Quantization Noise	6
2.2.2 kTC Noise	7
2.2.3 Jitter	8
2.3 Fundamental Characterization Units	9
2.3.1 Signal-to-Noise Ratio	9
2.3.2 Total Harmonic Distortion	13
2.3.3 Signal-to-Noise-and-Distortion Ratio	14
2.3.4 Dynamic Range	14
2.3.5 Spurious-Free Dynamic Range	15
2.3.6 Differential Nonlinearity	15
2.3.7 Integral Nonlinearity	16
2.3.8 Figure of Merit	17
2.4 ADC Types	18
2.4.1 Flash ADC	18
2.4.2 SAR ADC	19
2.4.3 Slope ADC	20
2.4.4 Sigma-Delta ADC	21
2.4.5 Pipelined ADC	22
2.4.6 Time-Interleaved ADC	23
2.5 State of the Art	24
3 Concept for a Software-Configurable ADC	31
3.1 Vision	31
3.2 First Iteration of a Software-Configurable ADC	32
3.3 Process Technology Choice	34

4	First ADC Chip	35
4.1	Overview SAR ADC	35
4.2	Technical Specifications	37
4.3	Asynchronous Operation	38
4.4	Capacitive Digital-To-Analog Converter	38
4.4.1	CDAC Switching Scheme	39
4.4.2	Implementation	44
4.5	Comparator	47
4.5.1	The Dynamic Latch-Based Comparator	47
4.5.2	Implementation	48
4.6	Sequencer	50
4.6.1	The classical Sequencer	50
4.6.2	Implementation	50
4.7	Input Buffer	52
4.7.1	Specifications	52
4.7.2	Implementation	53
4.8	Bootstrapped Switches	55
4.8.1	Fundamentals	55
4.8.2	Implementation	56
4.9	Delay Element	58
4.9.1	Introduction	58
4.9.2	Implementation	58
4.10	Metastability detector	60
4.11	Reference Buffer	61
4.12	Layout	61
5	Measurement Results of First ADC Chip	63
5.1	Printed Circuit Board	63
5.2	Measurement Setup	64
5.3	Delay Line Configuration	65
5.4	Maximum Sample Rate	65
5.5	Power Consumption	66
5.6	Maximum Input Signal Frequency	66
5.7	DNL and INL	68
5.8	Performance Summary	68
5.9	Discussion of the First Chip ADC	69
6	Second ADC Chip	71
6.1	Technical Specifications	71
6.2	Overview Pipelined SAR ADC	72
6.2.1	First Stage Bypass	73
6.2.2	Residue Interleaving	73
6.2.3	Self-Adjusted Duty Cycle	75
6.2.4	1.8 Volt Switches	76
6.3	Input buffer	78
6.4	Metastability	80
6.5	Sequencer	80

6.6	First Stage SAR ADC	81
6.6.1	CDAC	81
6.6.2	Comparator	84
6.7	Delay Element	85
6.8	Residue Amplifier	86
6.8.1	The Ring Amplifier	86
6.8.2	Implementation	88
6.9	Second Stage CDAC	90
6.10	Second Stage Comparator	92
6.11	Layout Overview	93
7	Measurement Results of Second ADC Chip	95
7.1	Printed Circuit Board	95
7.2	Measurement Setup	95
7.3	Low-Power Mode Measurements	96
7.3.1	Delay Line Configuration	96
7.3.2	Maximum Sample Rate	96
7.3.3	Power Consumption	97
7.3.4	Maximum Input Signal Frequency	98
7.3.5	DNL and INL	99
7.3.6	Performance Summary	100
7.4	High-Precision Mode Measurements	102
7.4.1	Erroneous Output Characteristic	102
7.4.2	First Stage ADC Investigation	103
7.4.3	Impact of Input Common-Mode Voltage	103
7.4.4	Power Consumption	105
7.4.5	SNDR and SFDR	106
7.4.6	DNL and INL	107
7.4.7	Performance Summary	108
7.5	Discussion of Second Chip ADC	109
7.5.1	Low-Power Mode	109
7.5.2	High-Precision Mode	110
8	Conclusion and Outlook	111
	Bibliography	xix

Information
Band / Volume 112
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